Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/478,372	NAKAMURA, KENJI	
Examiner	Art Unit	
Thanh X. Luu	2878	

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Class	Subclass	Date	Examiner
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250	559.38		
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396	104, 128		V
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
Same	as above	03/05	TXC		

(INCLUDING SEARCH STRATEGY)				
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